

Notice of References Cited	Application/Control No. 10/587,315	Applicant(s)/Patent Under Reexamination YAMADA ET AL.	
	Examiner JUAN E. VAUGHAN II	Art Unit 1795	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0224281 A1	12-2003	Ishizuka et al.	430/157
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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